Computer Vision in the Built Environment

1st Scan-to-BIM Challenge

Held in conjunction with the
IEEE Conference on Computer Vision and Pattern Recognition 2021

June 20, 2021

Second Place

2D FLOORPLAN RECONSTRUCTION

Jingdao Chen, Jisoo Park, Yosuke Yajima, & Seongyong Kim

Georgia Institute of Technology

James to

Fuxin Li, on behalf of the Organizing Committee





ALLVISION



